

Our Other ESD & Latch-Up Offerings

1. Multiple Thermo KeyTek MK.2 Zap ESD Master/Latch-Up Testers

- Up to 768 I/O Pins for ESD (HBM, MM) and Latch-Up
- Trailing Pulse Upgrade Included
- HBM Testing to Current JEDEC EIA/JESD22-A114, MIL STD 883, ESDA STM5.1 & AEC Q100-002
- Pre-Conditioning, State Read-Back & Full Control of Each Test Pin
- Up to 5 Separate V/I Supplies, Capable of 0-100V & 0-10A
- 64K Full Vectoring Per Pin with Read-Back; CLK Speed of up to 10 MHz
- Pre & Post Test Curve Test Capability

2. Thermo KeyTek RCDM3 Robotic CDM ESD Test System

- Fully Automated, Robotic Test System
- Uses Either Direct Charge or Field Charge Method
- Capable of Testing Devices of any Configuration or Geometry up to 50X50 mm Package Size
- Positioning Accuracy of 0.01 mm
- Consistent Test Head Speeds

3. Oryx EX11000S Automated Component Reliability Tester

- Fast Automated HBM/MM/Latch-up with **2016 Pin** Test Capability
- No Need for Non-Quadrant Based Testing
- Most Advanced Vector Generation Sub System
- SMU Measures Leakage & CT
- 7 Bias Supplies
- Multiple Device Testing
 - HBM from +/- 50 to 8000V
 - MM from +/- 50 to 2000V

4. Haefely PESD 3010 for Contact & Air Discharge Method

- Contact Discharge and Air Discharge at 30KV

“STS is a Technology Leader Providing Innovative Solutions”

SILICON TURNKEY SOLUTIONS
Test, Qualification & Sales Support
43174 Osgood Road,
Fremont, CA 94539
<http://siliconturnkey.com>
<http://esdlab.com>

Silicon Turnkey Solutions
ESD / LATCH-UP LAB

*STS Acquires Leading-Edge
ESD & Latch-up Testers.*

**INTRODUCING THE LATEST KEYTEK
ZAP MASTER MK.4**



*The Most Advanced ESD &
Latch-up Tester, Now Capable Of
Testing Devices Up To 2304 Pins.*

STS

Silicon Turnkey Solutions

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About STS

STS has established itself as a one-stop solution provider in the area of Specialty Assembly, Electrical Test, Qualification, Reliability and Product Screening. Our clients include Space, Defense & Military, Consumer Telecommunications and Medical, Computers and Automotive companies. With over 100 man years of experience in the industry, we provide the latest solutions for Graphics and Network Processors, Chip Sets, Asics, Memories, LAN/WAN and Consumer ICs, both pure digital and mixed signal. We are an ISO-9001:2000, QML and ITAR certified company. STS's high end technology solutions include:

Specialty Assembly

- Advanced Micro Flip Chip Packaging
- Specialty Packaging Solutions
- Hermetic for Military Application



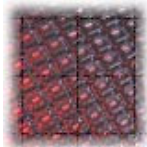
Test

- Program Development & Characterization
- High End Test Systems: Agilent 93K, Credence and LTX RF Testers
- Wide Range of High-pin Count Chipsets, Graphic Devices, High Speed LAN and Serial Bus Technologies as well as SoC Devices with High-speed and High-resolution ADC and DAC Cores Supported



Reliability /Qualification

- Full Environmental and Qualification Testing for Both Component (Level 1) and System Level (Level 2).
- ESD, Latch-up, HTOL, LTOL, Temp Cycling, HAST, THB, Pre-cond, C SAM, Group C and D Tests Per JEDEC, TELCORDIA, MIL Std., EIAJ, IEC, STACK, CECC standards



- Group A, B, C, and D devices per MIL-PRF-38535 and MIL-STD-883.

ESD & Latch-Up – Most Up-to-Date Equipment in the Industry

STS has raised the bar in the field of ESD and Latch up testing. Expanded capability with multiple systems that can test at 2K+ pins per device and added capacity expansion in the CDM, MM, and HBM tests makes us the undisputed leader that provides the most leading edge tools and engineering expertise for your device ESD & Latch-up needs.

Introducing the All New, Highly Automated ESD & Latch-Up System – MK.4



Wide-ranging Features of MK.4

- Fastest Automated HBM/MM/Latch-up with **2304 Pin** Test Capability
- HBM Range from 25V to 8KV in 1V Steps
- MM Range of 25V to 2KV in 1V Steps
- Latch-Up Testing with 256K Vectors/pin with Read-Back
- Up to 10 MHz Vector Rate
- 6 Independent Vector Voltage Levels
- Up to 8 Separate V/I Supplies
- Rapid Relay-based Operations
- Event Trigger Output
- Power Supply Sequencing
- Waveform Network: 12 Site HBM (100pF/1500) Pulse Source

- Multiple Device Selection
- Translation of Pin Type Test Requirements
- Latch up Current Capability > 10 AMPS
- Import & Export Data in Customizable Form
- Characterization that you can Manipulate
- Data Transferable to FTP & Built in Web server.

Meeting Wide Variety of Industry Standards

Human Body Model

- EIA/JEDEC JESD22-A114-D
- ESD-STM5.1 2001
- MIL-STD-883G, Method 3015.7
- AEC-Q100-002-Rev D

Machine Model

- EIA/JEDEC JESD22-A115-A
- ESD-STM5.2 1999
- AEC-Q100-003-Rev E

Charged Device Model

- EIA/JEDEC JESD22-C101C
- ESD-STM5.3.1 1999
- AEC-Q100-011-Rev B

Latch-up

- EIA/JEDEC JESD78
- AEC-Q100-004-Rev C

Electro-Thermally Induced Parasitic Gate Leakage Test

- AEC-Q100-006-Rev D

Air Discharge & Contact ESD Test

- IEC 61000-4-2
- IEC 801-2
- IEC 1000-4-2